TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (π-MOSVI)

2SK3561

Switching Regulator Applications

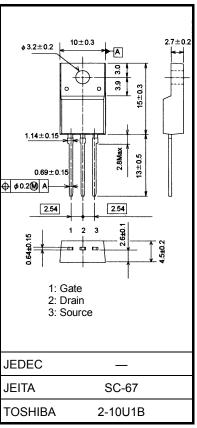
Unit: mm

- Low drain-source ON resistance: RDS (ON) = 0.75Ω (typ.)
- High forward transfer admittance: $|Y_{fs}| = 6.5S$ (typ.)
- Low leakage current: $I_{DSS} = 100 \, \mu \, A \, (V_{DS} = 500 \, V)$
- Enhancement mode: $V_{th} = 2.0 \sim 4.0 \text{ V (VDS} = 10 \text{ V, ID} = 1 \text{ mA})$

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Absolute Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit	
Drain-source voltage		V_{DSS}	500	V	
Drain-gate voltage ($R_{GS} = 20 \text{ k}\Omega$)		V_{DGR}	500	V	
Gate-source voltage		V_{GSS}	±30	V	
Drain current	DC (Note 1)	I _D	8		
	Pulse (t = 1 ms) (Note 1)	I _{DP}	32	Α	
Drain power dissipation (Tc = 25°C)		P _D	40	W	
Single pulse avalanche energy (Note 2)		E _{AS}	312	mJ	
Avalanche current		I _{AR}	8	Α	
Repetitive avalanche energy (Note 3)		E _{AR}	4	mJ	
Channel temperature		T _{ch}	150	°C	
Storage temperature range		T _{stg}	-55~150	°C	



Weight: 1.7 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Thermal Characteristics

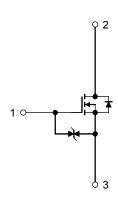
Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R _{th (ch-c)}	3.125	°C/W
Thermal resistance, channel to ambient	R _{th (ch-a)}	62.5	°C/W

Note 1: Ensure that the channel temperature does not exceed 150°C.

Note 2: $V_{DD} = 90 \text{ V}$, $T_{ch} = 25^{\circ}\text{C}(\text{initial})$, L = 8.3 mH, $I_{AR} = 8 \text{ A}$, $R_G = 25 \Omega$

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device. Please handle with caution.





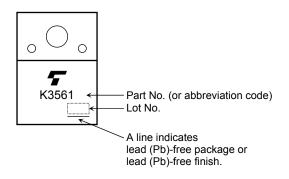
Electrical Characteristics (Ta = 25°C)

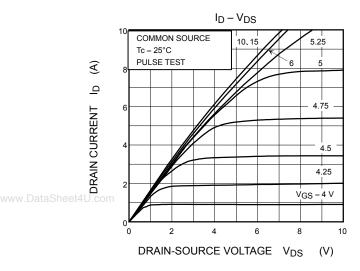
Chara	octeristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage curr	rent	I _{GSS}	$V_{GS}=\pm 25~V,~V_{DS}=0~V$	_	_	±10	μΑ
Gate-source brea	kdown voltage	V (BR) GSS	$I_G=\pm 10~\mu A,~V_{DS}=0~V$	±30	_	_	V
Drain cut-off current		I _{DSS}	V _{DS} = 500 V, V _{GS} = 0 V	_	_	100	μΑ
Drain-source brea	akdown voltage	V (BR) DSS	I _D = 10 mA, V _{GS} = 0 V	500			V
Gate threshold vo	ltage	V _{th}	V _{DS} = 10 V, I _D = 1 mA	2.0		4.0	V
Drain-source ON	resistance	R _{DS (ON)}	V _{GS} = 10 V, I _D = 4 A	_	0.75	0.85	Ω
Forward transfer	admittance	Y _{fs}	V _{DS} = 10 V, I _D = 4 A	3.0	6.5		S
Input capacitance C _{iss}		C _{iss}	V _{DS} = 25 V, V _{GS} = 0 V, f = 1 MHz	_	1050		pF
Reverse transfer capacitance		C _{rss}		_	10		
Output capacitance		Coss		_	110		
Switching time	Rise time	t _r	$\begin{array}{c c} 10 \text{ V} \\ \text{VGS} \\ 0 \text{ V} \end{array}$ $\begin{array}{c c} \text{I}_D = 4 \text{ A} & \text{V}_{\text{OUT}} \\ \text{V}_{\text{CD}} \approx 200 \text{ V} \end{array}$	_	26	_	
	Turn-on time	t _{on}		_	45	_	
	Fall time	t _f		_	38	_	ns
	Turn-off time	t _{off}	Duty ≤ 1%, t _W = 10 μs	_	130	_	
Total gate charge		Qg		_	28	_	
Gate-source charge		Q _{gs}	$V_{DD} \simeq 400 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 8 \text{ A}$	_	16	_	nC
Gate-drain charge		Q _{gd}		_	12	_	

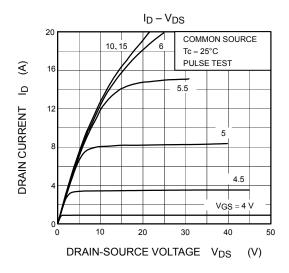
Source-Drain Ratings and Characteristics (Ta = 25°C)

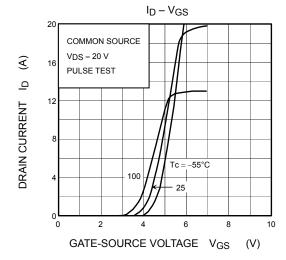
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I _{DR}	_	_	_	8	Α
Pulse drain reverse current (Note 1)	I _{DRP}	_	_	_	32	Α
Forward voltage (diode)	V _{DSF}	I _{DR} = 8 A, V _{GS} = 0 V	_	_	-1.7	V
Reverse recovery time	t _{rr}	$I_{DR} = 8 \text{ A}, V_{GS} = 0 \text{ V},$		1200		ns
Reverse recovery charge	Q _{rr}	dI _{DR} /dt = 100 A/μs	_	10		μС

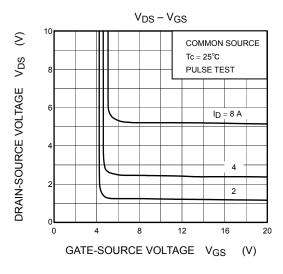
Marking

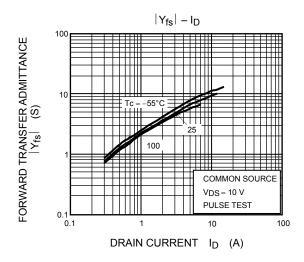


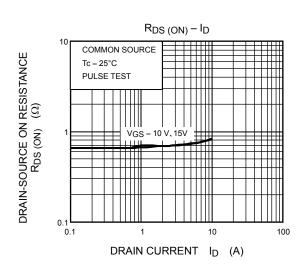


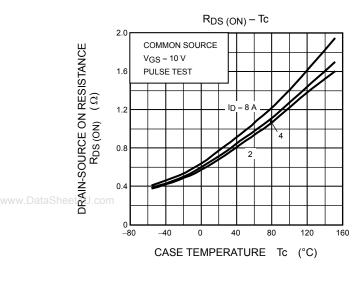


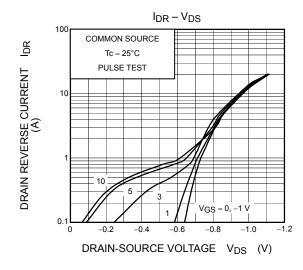


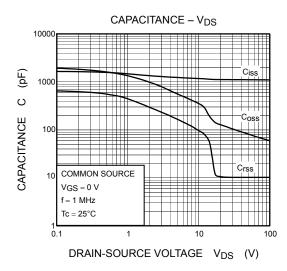


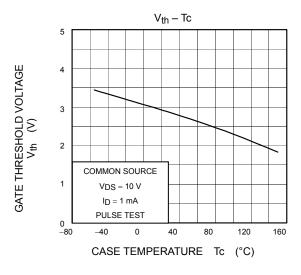


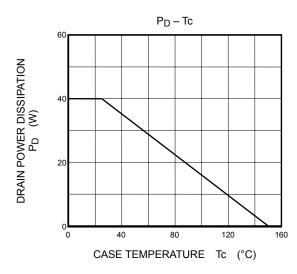


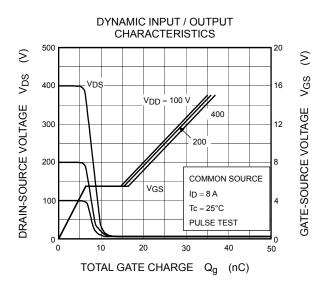


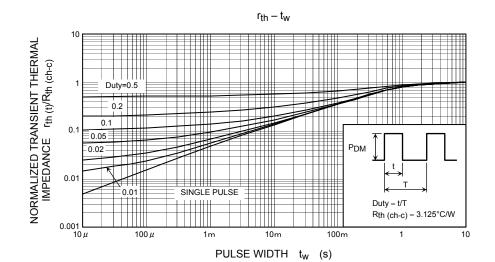




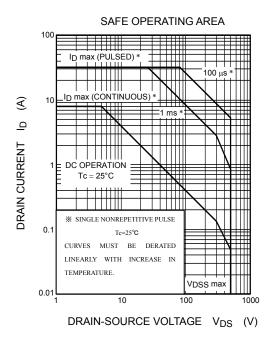


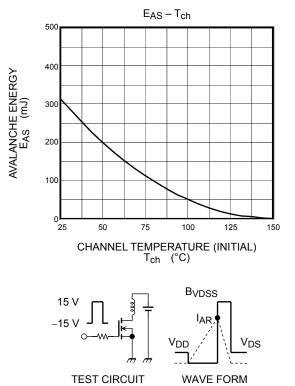






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$$\mathsf{E}_{AS} = \frac{1}{2} \cdot L \cdot l^2 \cdot \left(\frac{\mathsf{B}_{VDSS}}{\mathsf{B}_{VDSS} - \mathsf{V}_{DD}} \right)$$

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